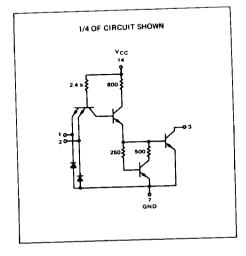
QUAD 2-INPUT "NAND" GATE (Open Collector)

MTTL III MC3100/3000 series

MC3104F · MC3004F MC3104L · MC3004L.P (74H01J.N)

(54H01J)



This device consists of four 2-input NAND gates with no output pull-up circuits. It can be used where the Wired-OR-function is required or for driving discrete components.



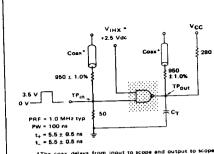
Positive Logic: 3 = 1 · 2 Negative Logic: 3 = 1 + 2

Input Loading Factor = 1 Output Loading Factor = 10

Total Power Dissipation = 88 mW typ/pkg Propagation Oslay Time = 8.0 ns typ

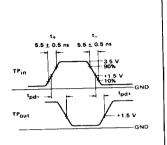
SWITCHING TIME TEST CIRCUIT

VOLTAGE WAVEFORMS AND DEFINITIONS



*The coax delays from input to scope and output to scope must be matched. The scope must be terminated in 50-ohm impedance. The 950-ohm resistor and the scope termination impedance constitute a 20:1 attenuator probe. Coax shall be CT-070-50 or equivalent.

 $\text{C}_{T}=25~\text{pF}\approx$ total parasitic capacitance, which includes probe, wiring, and load capacitances.



See General Information section for packaging.

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	2 1 1		أَ					WC3	MC3004 +2	0°C 20 +25°C 20	1.0	. 97	1.1 2.0 0.4	++	2 2 3	999	+		£ £	5.25 85.25	2	
									=	+75°C 20	-	1	TEST CHRREN	-i ⊨	VOLTAGE	PPLIED TO	PINS LIST	ED BELOW				
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	1	-55°C	Hin Max	1	3	ž	Min Mex	ž	ž	Ē	.* 8	•			$\ \cdot\ $	Ш		╂	=		·	:
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Forward Current	-	-2.0	2		L	-+-	1	,	8	n Adc		Ŀ		-	-	.		+	-	7	ŀ	2.7
Leakage Current		8			-+		+	+	1	Vdc	-	-	-	-				-+-	1	1	-	1
Breakdown Voltage BV _{IR}	-		5.5	.	+	-	-+-	1.5	1	Ϋ́	-	-						+		1		1
Clamp Voltage VD	- !	.			+	+	-+-	1	+	+	┼-		-			2			<u> </u>	.		-
Output Output Voltage Vol.					*	* 0			•	ĕ \$. .	+	- 2	1.		. '	-		z			:
Output Leakage 10.E.X.	× ×	. 250		250	250	250		250	3	+	1	-	-					=				9, 10, 12, 13
Ower Requirements (Total Device										¥ av	-	•				2 4 5		1	2	1.	ļ.	-
			1	96	98	38	-	2	36	mAdr					- 1	9, 10, 12, 13		1	16	-	 	9, 10, 12, 13
Power Supply Drain Ipple	# # K	3.2		-+-+	9.71	22.	1.1	g	17.5	m.Adc		a loc	-	-			1	1		-	-	
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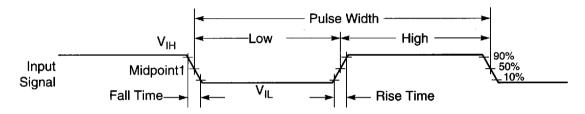
Since this is an inverting talls, power drain is minimized by grounding, the imputs to gates not under test.

24

ELECTRICAL CHARACTERISTICS

AC ELECTRICAL CHARACTERISTICS

The timing waveforms in the AC Electrical Characteristics are tested with a V_{IL} maximum of 0.5 V and a V_{IH} minimum of 2.4 V for all pins, except EXTAL, RESET, MODA, MODB, and MODC. These pins are tested using the input levels set forth in the DC Electrical Characteristics. AC timing specifications that are referenced to a device input signal are measured in production with respect to the 50% point of the respective input signal's transition. DSP56002 output levels are measured with the production test machine V_{OL} and V_{OH} reference levels set at 0.8 V and 2.0 V, respectively.



Note: The midpoint is $V_{IL} + (V_{IH} - V_{IL})/2$.

AA0179

Figure 2-1 Signal Measurement Reference